

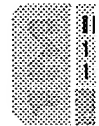
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L7	20753	(L6 xor L4) (L6 and L4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/22 21:27
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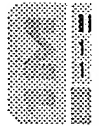
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(state of health&lt;in&gt;ti) &lt;and&gt; characteristic

☐ Check to search within this result set
**Results Key:****JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard**1 Fuzzy logic-based state-of-health determination of lead acid batteries**  
*Singh, P.; Reisner, D.;*
 Telecommunications Energy Conference, 2002. INTELEC. 24th Annual International , 29 Sept.-3 Oct. 2002  
 Pages:583 - 590

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**1 Wearable sensor system for wireless state-of-health determination cattle**

*Nagl, L.; Schmitz, R.; Warren, S.; Hildreth, T.S.; Erickson, H.; Andresen, D.;*  
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 Pages:3012 - 3015 Vol.4

[\[Abstract\]](#)   [\[PDF Full-Text \(424 KB\)\]](#)   **IEEE CNF**
**2 Battery state of health monitoring, combining conductance technology with other measurement parameters for real-time battery performance analysis**

*Cox, D.C.; Perez-Kite, R.;*  
 Telecommunications Energy Conference, 2000. INTELEC. Twenty-second International , 10-14 Sept. 2000  
 Pages:342 - 347

[\[Abstract\]](#)   [\[PDF Full-Text \(488 KB\)\]](#)   **IEEE CNF**
**3 Battery state of health estimation through coup de fouet**

*Bose, C.S.C.; Laman, F.C.;*  
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 Pages:597 - 601

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**4 The detection of the state of health of lead-acid batteries**

*Spath, V.; Jossen, A.; Doring, H.; Garche, J.;*  
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International , 19-23 Oct. 1997  
Pages:681 - 686

[\[Abstract\]](#) [\[PDF Full-Text \(352 KB\)\]](#) IEEE CNF

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**5 Monitoring the state of health of VRLA batteries through ohmic measurements**

*Waters, A.R.; Bullock, K.R.; Bose, C.S.C.;*  
Telecommunications Energy Conference, 1997. INTELEC 97., 19th  
International , 19-23 Oct. 1997  
Pages:675 - 680

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**6 Fuzzy logic-based state-of-health determination of lead acid batteries**

*Singh, P.; Reisner, D.;*  
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**7 Payload state of health monitoring design for next generation satellite constellations**

*Geib, P.L.; Cox, D.D.; Tomasi, A.M.;*  
Aerospace Conference Proceedings, 2002. IEEE , Volume: 1 , 9-16 March 2002  
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**8 Artificial intelligence reads battery state-of-health in three minutes**

*Buchmann, I.;*  
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12 Jan. 2001  
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**9 Analysis and interpretation of AC-measurements on batteries used to assess state-of-health and capacity-condition**

*Damlund, I.;*  
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International , 29 Oct.-1 Nov. 1995  
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**10 Determining the state-of-health of maintenance-free aircraft batteries**

*Vutetakis, D.G.; Viswanathan, V.V.;*  
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Annual , 10-13 Jan. 1995  
Pages:13 - 18

[\[Abstract\]](#) [\[PDF Full-Text \(428 KB\)\]](#) IEEE CNF

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**11 Analysis and interpretation of conductance measurements used to assess the state-of-health of valve regulated lead acid batteries**

*Feder, D.O.; Hlavac, M.J.;*

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Pages:282 - 291

[\[Abstract\]](#) [\[PDF Full-Text \(520 KB\)\]](#) IEEE CNF

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**12 Field and laboratory studies to assess the state of health of valve-regulated lead acid and other battery technologies using conductance testing**

*Hlavac, M.J.; Feder, D.O.; Croda, T.G.; Champlin, K.S.;*

Telecommunications Energy Conference, 1993. INTELEC '93. 15th International , Volume: 2 , 27-30 Sept. 1993

Pages:375 - 383 vol.2

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**13 Field and laboratory studies to assess the state of health of valve-regulated lead acid batteries. I Conductance/capacity correlation studies**

*Feder, D.O.; Croda, T.G.; Champlin, K.S.; Hlavac, M.J.;*

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**14 Determination of the state-of-health of VRLA batteries by means of noise measurements**

*Baert, D.H.J.; Vervaet, A.A.K.;*

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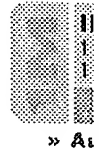
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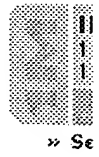
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<b>Application Number</b> 	<b>Application N .</b> 09/933,743	<b>Applicant(s)</b> TINNEMEYER, JORN
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Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	linden-david.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/22 18:23
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L4	148	706/1.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/22 18:33
L5	191	320/127.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/22 18:34
L6	0	5 and 2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/22 18:35
L7	339	(4 xor 5) (4 and 5)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/22 18:36
L8	18449	ross.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/22 18:37
L9	2	("6072299" "5977750").pn.	USPAT	OR	ON	2004/12/22 18:43
L10	66	("4800336"   "4876513"   "4885523"   "5130659"   "5444378"   "5455499"   "5625291"   "5631540"   "5721482").PN. OR ("5977750"   "6072299").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/22 18:51

L11	594	(1 xor 2) (1 and 2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/22 18:44
L12	2308	(11 xor 3) (11 and 3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/22 18:44
L13	20753	(12 xor 8) (12 and 8)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/22 18:44
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